Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/646,708	ECKER ET AL.
Examiner	Art Unit
Patrick J. Lee	2878

SEARCHED					
Class	Subclass	Date	Examiner		
250	227.14, 227.16	12/12/2005	PL		
385	10, 12	12/12/2005	PL		
385	13, 37	12/12/2005	PL		
Updated	search	5/30/2006	PL		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Consulted w/ S. Allen	8/4/2005	PL		
Consulted w/ B. Healy AU 2883 CL 385	8/9/2005	PL		
East (See attached)	8/9/2005	PL		
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	12/12/2005	PL		
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	5/30/2006	PL		